

# CD74HC533, CD74HCT533, CD74HC563, CD74HCT563

## High Speed CMOS Logic Octal Inverting Transparent Latch, Three-State Outputs

### Features

- **Common Latch-Enable Control**
- **Common Three-State Output Enable Control**
- **Buffered Inputs**
- **Three-State Outputs**
- **Bus Line Driving Capacity**
- **Typical Propagation Delay = 13ns at  $V_{CC} = 5V$ ,  $C_L = 15pF$ ,  $T_A = 25^\circ C$  (Data to Output)**
- **Fanout (Over Temperature Range)**
  - Standard Outputs . . . . . 10 LSTTL Loads
  - Bus Driver Outputs . . . . . 15 LSTTL Loads
- **Wide Operating Temperature Range . . .  $-55^\circ C$  to  $125^\circ C$**
- **Balanced Propagation Delay and Transition Times**
- **Significant Power Reduction Compared to LSTTL Logic ICs**
- **HC Types**
  - 2V to 6V Operation
  - High Noise Immunity:  $N_{IL} = 30\%$ ,  $N_{IH} = 30\%$  of  $V_{CC}$  at  $V_{CC} = 5V$
- **HCT Types**
  - 4.5V to 5.5V Operation
  - Direct LSTTL Input Logic Compatibility,  $V_{IL} = 0.8V$  (Max),  $V_{IH} = 2V$  (Min)
  - CMOS Input Compatibility,  $I_I \leq 1\mu A$  at  $V_{OL}$ ,  $V_{OH}$

### Description

The Harris CD74HC533, CD74HCT533, CD74HC563, and CD74HCT563 are high speed Octal Transparent Latches manufactured with silicon gate CMOS technology. They possess the low power consumption of standard CMOS integrated circuits, as well as the ability to drive 15 LSTTL devices.

The outputs are transparent to the inputs when the latch enable ( $\overline{LE}$ ) is high. When the latch enable ( $\overline{LE}$ ) goes low the data is latched. The output enable ( $\overline{OE}$ ) controls the three-state outputs. When the output enable ( $\overline{OE}$ ) is high the outputs are in the high impedance state. The latch operation is independent to the state of the output enable.

The CD74HC533 and CD74HCT533 are identical in function to the CD74HC563 and CD74HCT563 but have different pinouts. The CD74HC533 and CD74HCT533 are similar to the CD74HC373 and CD74HCT373; the latter are non-inverting types.

### Ordering Information

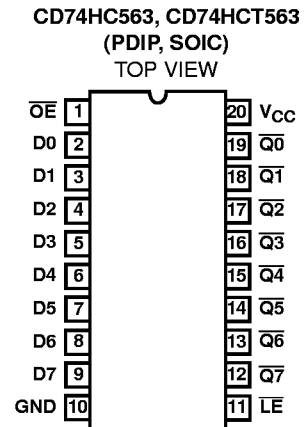
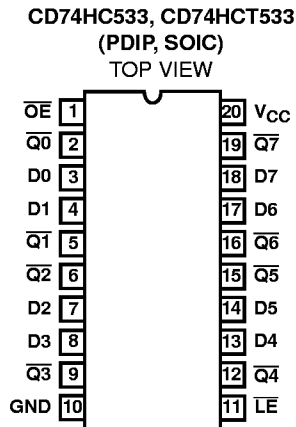
PART NUMBER	TEMP. RANGE ( $^\circ C$ )	PACKAGE	PKG. NO.
CD74HC533E	-55 to 125	20 Ld PDIP	F20.3
CD74HCT533E	-55 to 125	20 Ld PDIP	E20.3
CD74HC563E	-55 to 125	20 Ld PDIP	E20.3
CD74HCT563E	-55 to 125	20 Ld PDIP	E20.3
CD74HCT563M	-55 to 125	20 Ld SOIC	M20.3

#### NOTES:

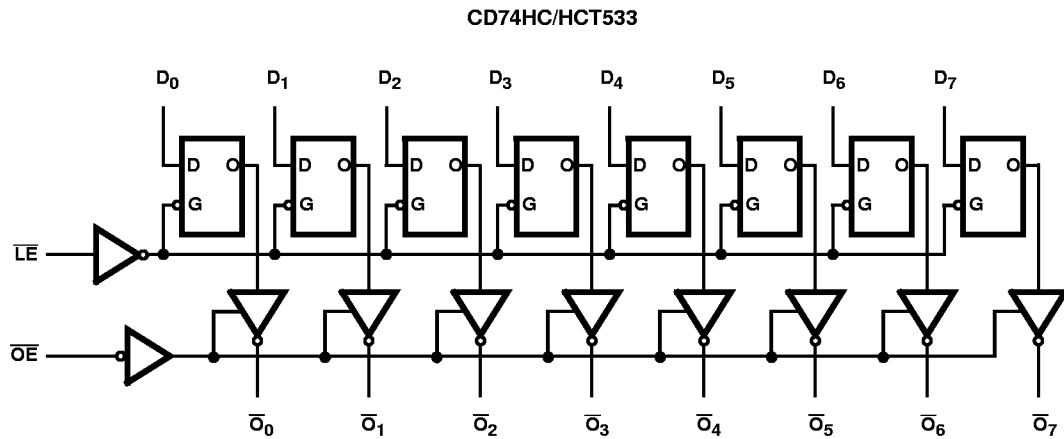
1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer and die for this part number are available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

# CD74HC533, CD74HCT533, CD74HC563, CD74HCT563

## Pinouts



## Functional Block Diagram



TRUTH TABLE

OUTPUT ENABLE	LATCH ENABLE	DATA	Q OUTPUT
L	H	H	L
L	H	L	H
L	L	l	H
L	L	h	L
H	X	X	Z

NOTE: H = High Voltage Level, L = Low Voltage Level, X = Don't Care, Z = High Impedance State, l = Low voltage level one set-up time prior to the high to low latch enable transition, h = High voltage level one set-up time prior to the high to low latch enable transition.

## CD74HC533, CD74HCT533, CD74HC563, CD74HCT563

### Absolute Maximum Ratings

DC Supply Voltage, $V_{CC}$ .....	-0.5V to 7V
DC Input Diode Current, $I_{IK}$	
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$ .....	$\pm 20mA$
DC Output Diode Current, $I_{OK}$	
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$ .....	$\pm 20mA$
DC Drain Current, per Output, $I_O$	
For $-0.5V < V_O < V_{CC} + 0.5V$ .....	$\pm 35mA$
DC Output Source or Sink Current per Output Pin, $I_O$	
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$ .....	$\pm 25mA$
DC $V_{CC}$ or Ground Current, $I_{CC}$ .....	$\pm 50mA$

### Thermal Information

Thermal Resistance (Typical, Note 3)	$\theta_{JA}$ ( $^{\circ}C/W$ )
PDIP Package .....	125
SOIC Package .....	120
Maximum Junction Temperature .....	150 $^{\circ}C$
Maximum Storage Temperature Range .....	-65 $^{\circ}C$ to 150 $^{\circ}C$
Maximum Lead Temperature (Soldering 10s) .....	300 $^{\circ}C$ (SOIC - Lead Tips Only)

### Operating Conditions

Temperature Range, $T_A$ .....	-55 $^{\circ}C$ to 125 $^{\circ}C$
Supply Voltage Range, $V_{CC}$	
HC Types .....	.2V to 6V
HCT Types .....	4.5V to 5.5V
DC Input or Output Voltage, $V_I$ , $V_O$ .....	0V to $V_{CC}$
Input Rise and Fall Time	
2V .....	1000ns (Max)
4.5V .....	500ns (Max)
6V .....	400ns (Max)

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTE:

- $\theta_{JA}$  is measured with the component mounted on an evaluation PC board in free air.

### DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		$V_{CC}$ (V)	25 $^{\circ}C$			-40 $^{\circ}C$ TO 85 $^{\circ}C$		-55 $^{\circ}C$ TO 125 $^{\circ}C$		UNITS
		$V_I$ (V)	$I_O$ (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<b>HC TYPES</b>												
High Level Input Voltage	$V_{IH}$	-	-	2	1.5	-	-	1.5	-	1.5	-	V
				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input Voltage	$V_{IL}$	-	-	2	-	-	0.5	-	0.5	-	0.5	V
				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output Voltage CMOS Loads	$V_{OH}$	$V_{IH}$ or $V_{IL}$	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output Voltage TTL Loads	$V_{OH}$	$V_{IH}$ or $V_{IL}$	-6	4.5	3.98	-	-	3.84	-	3.7	-	V
			-7.8	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	$V_{OL}$	$V_{IH}$ or $V_{IL}$	0.02	2	-	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads	$V_{OL}$	$V_{IH}$ or $V_{IL}$	6	4.5	-	-	0.26	-	0.33	-	0.4	V
			7.8	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	$I_I$	$V_{CC}$ or GND	-	6	-	-	$\pm 0.1$	-	$\pm 1$	-	$\pm 1$	$\mu A$
Quiescent Device Current	$I_{CC}$	$V_{CC}$ or GND	0	6	-	-	8	-	80	-	160	$\mu A$

**CD74HC533, CD74HCT533, CD74HC563, CD74HCT563**

**DC Electrical Specifications (Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS		V <sub>CC</sub> (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
		V <sub>I</sub> (V)	I <sub>O</sub> (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Three-State Leakage Current	-	V <sub>IL</sub> or V <sub>IH</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	6	-	-	±0.5	-	±5	-	±10	μA
<b>HCT TYPES</b>												
High Level Input Voltage	V <sub>IH</sub>	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I <sub>I</sub>	V <sub>CC</sub> to GND	-	5.5	-	-	±0.1	-	±1	-	±1	μA
Quiescent Device Current	I <sub>CC</sub>	V <sub>CC</sub> or GND	0	5.5	-	-	8	-	80	-	160	μA
Three-State Leakage Current	-	V <sub>IL</sub> or V <sub>IH</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5	-	-	±0.5	-	±5	-	±10	μA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load (Note 4)	ΔI <sub>CC</sub>	V <sub>CC</sub> -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μA

NOTE:

- For dual-supply systems theoretical worst case (V<sub>I</sub> = 2.4V, V<sub>CC</sub> = 5.5V) specification is 1.8mA.

**HCT Input Loading Table**

INPUT	UNIT LOADS
D0 - D7	0.15
$\overline{LE}$	0.30
$\overline{OE}$	0.55

NOTE: Unit Load is ΔI<sub>CC</sub> limit specified in DC Electrical Specifications table, e.g., 360μA max at 25°C.

**CD74HC533, CD74HCT533, CD74HC563, CD74HCT563**

**Prerequisite For Switching Specifications**

PARAMETER	SYMBOL	TEST CONDITIONS	V <sub>CC</sub> (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<b>HC TYPES</b>											
LE Pulse Width	t <sub>w</sub>	-	2	80	-	-	100	-	120	-	ns
			4.5	16	-	-	20	-	24	-	ns
			6	14	-	-	17	-	20	-	ns
Set-up Time Data to LE	t <sub>SU</sub>	-	2	50	-	-	65	-	75	-	ns
			4.5	10	-	-	13	-	15	-	ns
			6	9	-	-	11	-	13	-	ns
Hold Time, Data to LE (533)	t <sub>H</sub>	-	2	35	-	-	45	-	55	-	ns
			4.5	7	-	-	9	-	11	-	ns
			6	6	-	-	8	-	7	-	ns
Hold Time, Data to LE (563)	t <sub>H</sub>	-	2	4	-	-	4	-	4	-	ns
			4.5	4	-	-	4	-	4	-	ns
			6	4	-	-	4	-	4	-	ns
<b>HCT TYPES</b>											
LE Pulse Width	t <sub>w</sub>	-	4.5	16	-	-	20	-	24	-	ns
Set-up Time Data to LE	t <sub>w</sub>	-	4.5	10	-	-	13	-	15	-	ns
Hold Time, Data to LE (533)	t <sub>H</sub>	-	4.5	8	-	-	10	-	12	-	ns
Hold Time, Data to LE (563)	t <sub>H</sub>	-	4.5	5	-	-	5	-	5	-	ns

**Switching Specifications** Input t<sub>p</sub>, t<sub>f</sub> = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V <sub>CC</sub> (V)	25°C		-40°C TO 85°C	-55°C TO 125°C	UNITS
				TYP	MAX	MAX	MAX	
<b>HC TYPES</b>								
Propagation Delay, Data to Qn (HC533)	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	165	205	250	ns
			4.5	-	33	41	50	ns
			6	-	28	35	43	ns
		C <sub>L</sub> = 15pF	5	13	-	-	-	ns
Propagation Delay, Data to Qn (HC563)	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
Propagation Delay, LE to Qn (HC533)	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	175	220	265	ns
			4.5	-	35	44	53	ns
			6	-	30	37	45	ns
		C <sub>L</sub> = 15pF	5	14	-	-	-	ns
Propagation Delay, LE to Qn (HC563)	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	165	205	250	ns
			4.5	-	33	41	50	ns
			6	-	28	35	43	ns
		C <sub>L</sub> = 15pF	5	13	-	-	-	ns

**CD74HC533, CD74HCT533, CD74HC563, CD74HCT563**

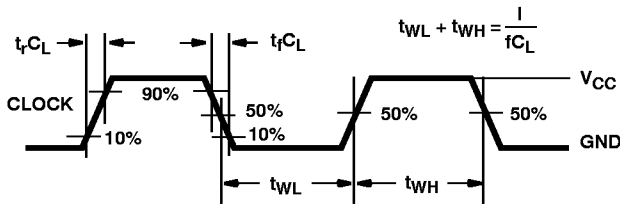
**Switching Specifications** Input  $t_r, t_f = 6\text{ns}$  (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS	$V_{CC}$ (V)	25°C		-40°C TO 85°C	-55°C TO 125°C	UNITS
				TYP	MAX	MAX	MAX	
Enable Times (HC533)	$t_{PZH}, t_{PZL}$	$C_L = 50\text{pF}$	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		$C_L = 15\text{pF}$	5	12	-	-	-	ns
Disable Times (HC533)	$t_{PHZ}, t_{PLZ}$	$C_L = 50\text{pF}$	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		$C_L = 15\text{pF}$	5	12	-	-	-	ns
Enable and Disable Times (HC563)	$t_{PZH}, t_{PZL}, t_{PHZ}, t_{PLZ}$	$C_L = 50\text{pF}$	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		$C_L = 15\text{pF}$	5	12	-	-	-	ns
Input Capacitance	$C_I$	-	-	-	10	10	10	pF
Three-State Output Capacitance	$C_O$	-	-	-	20	20	20	pF
Power Dissipation Capacitance (Notes 5, 6)	$C_{PD}$	-	5	42	-	-	-	pF
<b>HCT TYPES</b>								
Propagation Delay, Data to Qn (HC/HCT533)	$t_{PLH}, t_{PHL}$	$C_L = 50\text{pF}$	4.5	-	34	43	51	ns
		$C_L = 15\text{pF}$	5	14	-	-	-	ns
Propagation Delay, Data to Qn (HC/HCT563)	$t_{PLH}, t_{PHL}$	$C_L = 50\text{pF}$	4.5	-	30	38	45	ns
		$C_L = 15\text{pF}$	5	12	-	-	-	ns
Propagation Delay, $\overline{LE}$ to Qn (HC/HCT533)	$t_{PLH}, t_{PHL}$	$C_L = 50\text{pF}$	4.5	-	38	48	57	ns
		$C_L = 15\text{pF}$	5	16	-	-	-	ns
Propagation Delay, $\overline{LE}$ to Qn (HC/HCT563)	$t_{PZL}, t_{PZH}$	$C_L = 50\text{pF}$	4.5	-	35	44	53	ns
		$C_L = 15\text{pF}$	5	14	-	-	-	ns
Enable Times (HC/HCT533)	$t_{PLZ}, t_{PZH}$	$C_L = 50\text{pF}$	4.5	-	35	44	53	ns
		$C_L = 15\text{pF}$	5	14	-	-	-	ns
Disable Times (HC/HCT533)	$t_{TLH}, t_{THL}$	$C_L = 50\text{pF}$	4.5	-	30	38	45	ns
		$C_L = 15\text{pF}$	5	12	-	-	-	ns
Enable and Disable Times (HC/HCT563)	$t_{PZH}, t_{PZL}, t_{PHZ}, t_{PLZ}$	$C_L = 50\text{pF}$	4.5	-	35	44	53	ns
		$C_L = 15\text{pF}$	5	14	-	-	-	ns
Input Capacitance	$C_I$	-	-	-	10	10	10	pF
Power Dissipation Capacitance (Notes 5, 6)	$C_{PD}$	-	5	42	-	-	-	pF

NOTES:

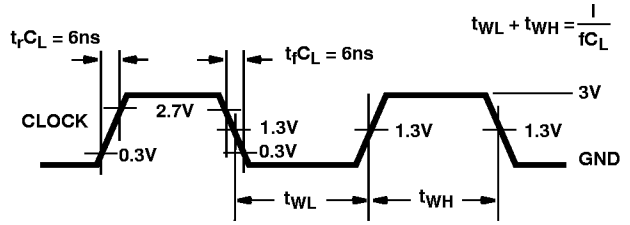
- $C_{PD}$  is used to determine the no-load dynamic power consumption, per latch.
- $P_D$  (total power per latch) =  $C_{PD} V_{CC}^2 f_i + \sum C_L V_{CC}^2 f_o$  where  $f_i$  = Input Frequency,  $f_o$  = Output Frequency,  $C_L$  = Output Load Capacitance,  $V_{CC}$  = Supply Voltage.

Test Circuits and Waveforms



NOTE: Outputs should be switching from 10% V<sub>CC</sub> to 90% V<sub>CC</sub> in accordance with device truth table. For f<sub>MAX</sub>, input duty cycle = 50%.

FIGURE 1. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH



NOTE: Outputs should be switching from 10% V<sub>CC</sub> to 90% V<sub>CC</sub> in accordance with device truth table. For f<sub>MAX</sub>, input duty cycle = 50%.

FIGURE 2. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

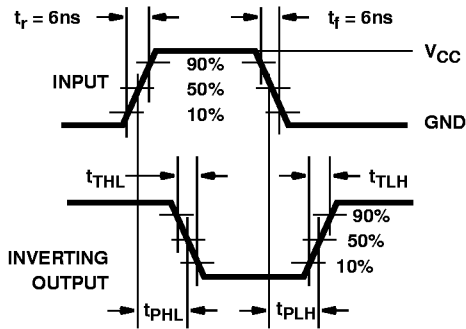


FIGURE 3. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

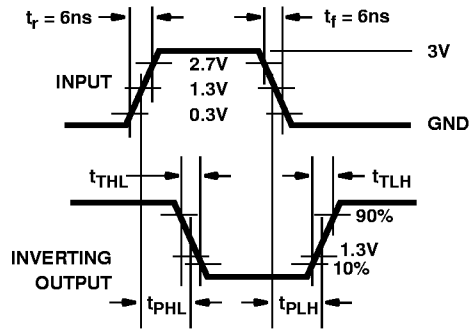


FIGURE 4. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

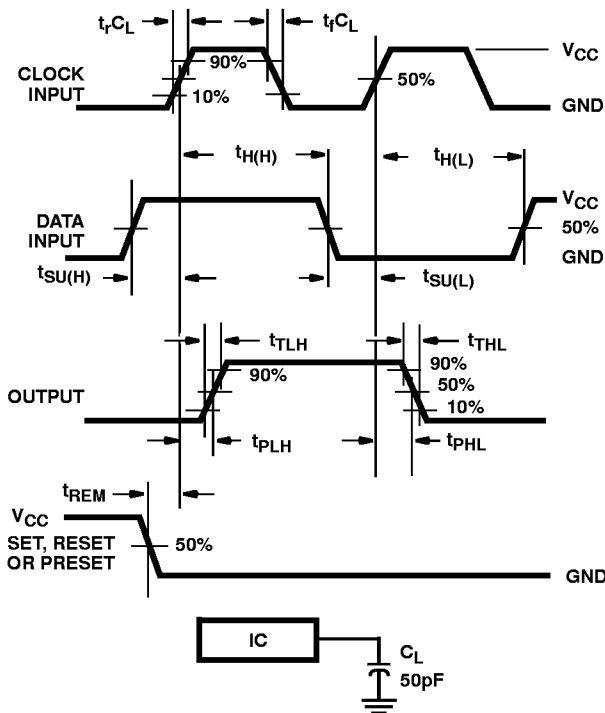


FIGURE 5. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

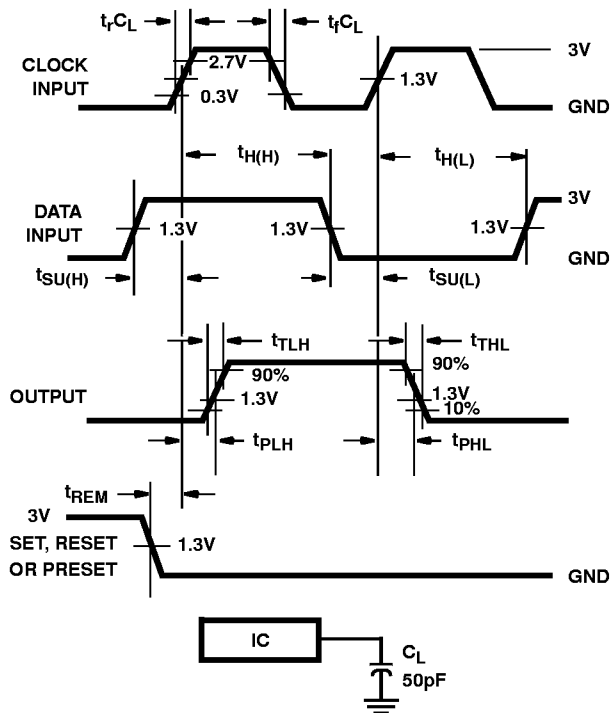


FIGURE 6. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

**Test Circuits and Waveforms** (Continued)

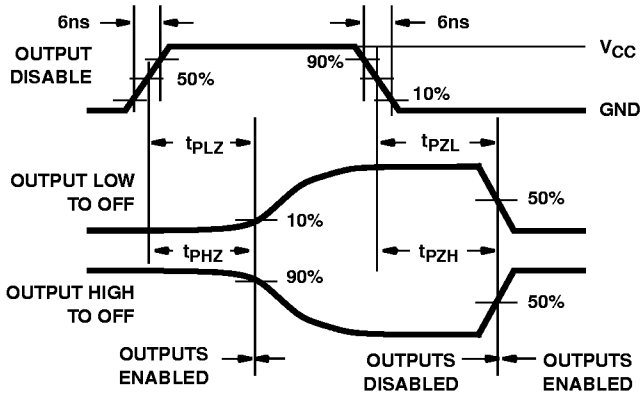


FIGURE 7. HC THREE-STATE PROPAGATION DELAY WAVEFORM

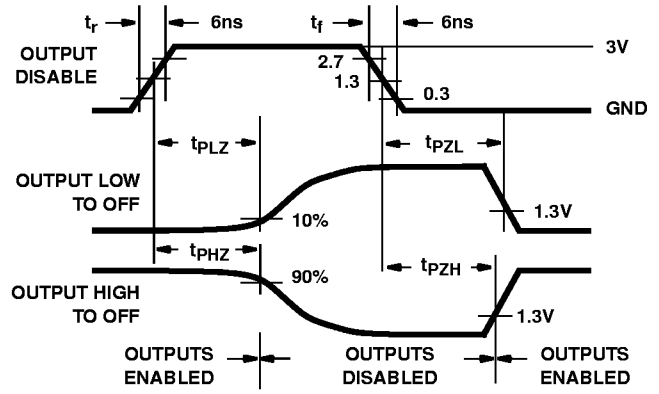
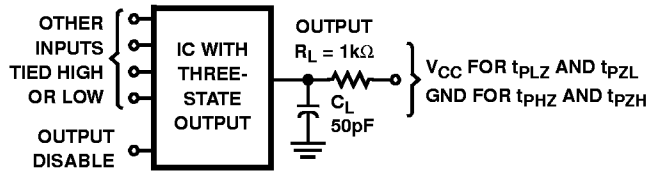


FIGURE 8. HCT THREE-STATE PROPAGATION DELAY WAVEFORM



NOTE: Open drain waveforms  $t_{pLZ}$  and  $t_{pZL}$  are the same as those for three-state shown on the left. The test circuit is Output  $R_L = 1k\Omega$  to  $V_{CC}$ .  $C_L = 50pF$ .

FIGURE 9. HC AND HCT THREE-STATE PROPAGATION DELAY TEST CIRCUIT